

**Table 1.** Selected geometric parameters ( $\text{\AA}$ ,  $^\circ$ )

C1—C4	1.531 (1)	C5—N1	1.136 (1)
C4—C5	1.475 (1)	C6—N2	1.133 (1)
C4—C6	1.476 (1)		
C5—C4—C6	108.9 (8)	N1—C5—C4	177.2 (1)
C5—C4—C1	112.3 (8)	N2—C6—C4	179.5 (1)
C6—C4—C1	112.0 (7)		

Reflection intensities were evaluated by profile fitting of a 96-step peak scan using a  $2\theta$  shell procedure (Diamond, 1969) and then corrected for Lorentz–polarization effects. Standard uncertainties,  $\sigma(I)$ , were estimated from counting statistics. H atoms have been treated isotropically [ $U_{iso}$  varies from 0.035 (3) to 0.061 (4)  $\text{\AA}^2$ ]. C—H bond lengths range from 0.95 (1) for C4—H4 to 1.01 (2)  $\text{\AA}$  for C3—H3. All calculations were performed on a  $\mu$ -VAX 3400 and on an AXP DecStation 3000/400.

Data collection: *P3/V* (Siemens, 1989). Cell refinement: *P3/V*. Data reduction: *XDISK* (Siemens, 1990). Program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997*b*). Program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997*a*). Molecular graphics: *XPW* (Siemens, 1996). Software used to prepare material for publication: *PARST95* (Nardelli, 1995) and *SHELXL97*.

We would like to express our gratitude, for support and aid, to the Italian MURST and to the ‘Centro Interdipartimentale di Servizi per la Diffrattometria a Raggi X’ of the University of Messina.

Supplementary data for this paper are available from the IUCr electronic archives (Reference: NA1363). Services for accessing these data are described at the back of the journal.

## References

- Bozio, R. & Pecile, C. (1991). *Advances in Spectroscopy*, Vol. 10. *Spectroscopy of Advanced Materials*. New York: John Wiley & Sons.
- Burrows, P. E., Shen, Z., McCarty, D. M., Forrest, S. R., Cronin, J. A. & Thompson, M. E. (1996). *J. Appl. Phys.* **79**, 7911–8006.
- Cimrova, V. & Neher, D. (1996). *Synthetic Metals*, **76**, 125–128.
- Corfield, P. W. R. & La Placa, S. J. (1996). *Acta Cryst. B52*, 384–387.
- Diamond, R. (1969). *Acta Cryst. A25*, 43–55.
- Duan, H., Cowan, D. O. & Kruger, J. (1993). *J. Electrochem. Soc.* **140**, 2807–2815.
- Epstein, A. J. & Reiff, W. M. (1988). *Chem. Rev.* **88**, 201–212.
- Ferraro, J. R. & Williams, J. M. (1987). *Introduction to Synthetic Electrical Conductors*. New York: Academic Press.
- Kalinowski, J., Di Marco, P., Cocchi, M., Fattori, V., Camaioni, N. & Duff, J. (1996). *Appl. Phys. Lett.* **68**, 2317–2319.
- Kopfmann, G. & Huber, R. (1968). *Acta Cryst. A24*, 348–351.
- Marks, T. J. (1990). *Angew. Chem. Int. Ed. Engl.* **29**, 857–866.
- Melby, R. L., Harder, R. J., Hertler, W. R., Mahler, W., Benson, R. E. & Mochel, W. E. (1962). *J. Am. Chem. Soc.* **84**, 3374–3383.
- Miller, J. S. (1981–1983). *Extended Linear Chain Compounds*, Vols 1–3. New York: Joel S. Miller.
- Nardelli, M. (1995). *PARST95* (release locally modified). *J. Appl. Cryst.* **28**, 659.
- Rinaldi, R., Lomascolo, M., Gigli, G., Cingolani, R., Arena, A., Martino, G., Patané, S., Saitta, G. & Girlanda, R. (1998). *Phys. Rev. B*, **57**, R9396.
- Sheldrick, G. M. (1997*a*). *SHELXL97. Program for the Refinement of Crystal Structures*. University of Göttingen, Germany.
- Sheldrick, G. M. (1997*b*). *SHELXS97. Program for the Solution of Crystal Structures*. University of Göttingen, Germany.
- Siemens (1989). *P3/V*. Release 4.21/V. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
- Siemens (1990). *XDISK. Data Reduction Program*. Release 4.21/V. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
- Siemens (1996). *XPW*. Release 5.05. Siemens Industrial Automation Inc., Analytical Instrumentation, Madison, Wisconsin, USA.
- Ulman, A. (1996). *Chem. Rev.* **96**, 1533–1554.
- Viossat, B., Tomas, A., Dung, N. H., Mettey, Y. & Vierfond, J. M. (1995). *Acta Cryst. C51*, 1896–1898.

*Acta Cryst.* (1998). **C54**, 2005–2007

## 2'-(1,3-Dithiolan-2-ylidene)-4'-(1,3-dithiol-2-ylidene)spiro[1,3-dithiole-2,5'-(4'H-5',6'-dihydro-1',3'-dithiapentalene)], the Self-Condensation Product of an Extended Tetrathiafulvalene Derivative

CÉCILE MÉZIÈRE,<sup>a</sup> MARC SALLÉ<sup>b</sup> AND MARC FOURMIGUÉ<sup>a</sup>

<sup>a</sup>*Institut des Matériaux de Nantes, UMR 6502 CNRS-Université de Nantes, BP 32229, 2, Rue de la Houssinière, 44322 Nantes CEDEX 03, France, and <sup>b</sup>Ingénierie Moléculaire et Matériaux Organiques, UMR 6501 CNRS-Université d'Angers, 2, Bd Lavoisier, 49045 Angers CEDEX, France. E-mail: fourmigue@cnrs-imn.fr*

(Received 19 May 1998; accepted 20 July 1998)

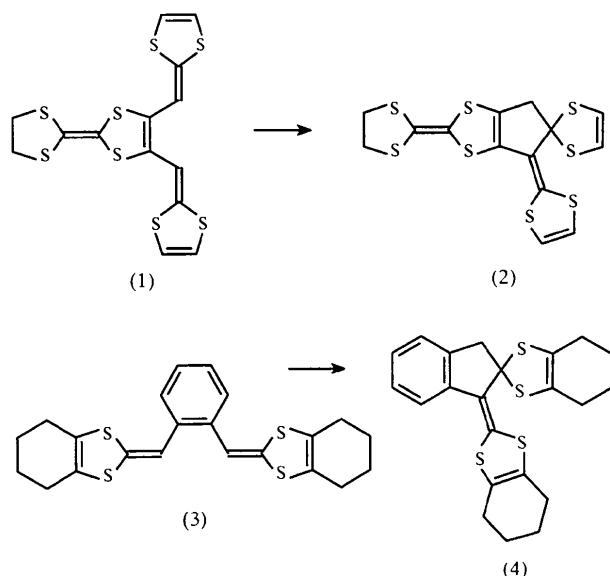
## Abstract

Silica-gel treatment of the extended tetrathiafulvalene derivative 2,3-bis(1,4-dithiafulven-6-yl)-6,7-dihydro-tetrathiafulvalene, bearing two 1,4-dithiafulven-6-yl groups in vicinal positions, afforded the title compound,  $C_{14}H_{10}S_8$ , as a cyclization product. While one dithiafulvenyl group is still conjugated with the tetrathiafulvalene moiety, the other one gives rise to a strongly folded 1,3-dithiole group linked to the molecule through a spiro-C atom. Two short non-bonding intramolecular 1,5-S···S contacts are also identified in the title compound.

## Comment

Extended tetrathiafulvalene derivatives such as (1) (see scheme below) have proved to be interesting candidates as precursors for the synthesis of novel organic conducting materials (Sallé *et al.*, 1996). We recently reported that the electrocrystallization of (1) in the presence of  $n\text{-Bu}_4\text{NClO}_4$  affords a 1:1 salt with  $\text{ClO}_4^-$  (Sallé *et al.*, 1993). This salt exhibits a novel mode of overlap, which allows the outer dithiafulvenyl groups of (1) to interleave in a direction perpendicular to the stacking axis.

However, other attempts to electrocrystallize this donor proved very disappointing. One possible explanation lies in the difficult purification of (1), since attempted chromatography (on silica gel) leads to its irreversible degradation. Attempts to substitute deactivated alumina for silica gel proved unsuccessful. An intramolecular transformation has already been identified in similar systems bearing two dithiafulvalenyl groups, such as (3), from which an acid-catalyzed process was shown to generate the novel spiro heterocycle (4), whose structure has been reported (Benahmed-Gasmi *et al.*, 1993; Frère *et al.*, 1994). During our purification trials of (1), we isolated a similar cyclized compound, (2), crystallized from CS<sub>2</sub>, whose structure is described here.



Important bond distances in the conjugated part of (2) are given in Table 1. The C—S bond lengths of the conjugated part of the molecule compare favourably with those observed, for example, in the neutral tetra-thiafulvalene (1.72–1.76 Å; Cooper *et al.*, 1971), while the C—S bonds involving *Csp*<sup>3</sup> atoms (C5, C6 and C8) are notably longer. Except for the outer ethylenic bridge (C5=C6), the dihydrotetrathiafulvalene moiety is almost planar, with a folding angle between the S3/C4/S4 and C3/S1/C1/C2/S2 mean planes of 2.2 (5)<sup>o</sup>, while atoms C5 and C6 are displaced from the S3/C4/S4 mean plane by 0.165 (9) and 0.819 (9) Å, respectively. The dithiafulvalene ring (built on S5 and S6) is nearly coplanar [1.7 (2)<sup>o</sup>] with the dithiole ring (built on S1 and S2) of the tetrathiafulvalene moiety, confirming the extended  $\pi$  delocalization. On the other hand, the new C1/C2/C7/C8/C11 ring is slightly distorted [atoms C7 and C8 are displaced above and below the C1/C2/C11 mean plane by 0.19 (1) and 0.09 (1) Å, respectively], and the spiro-linked dithiole ring (built on S7 and S8) is strongly folded [35.1 (2)<sup>o</sup>] along the S7···S8 axis, away

from the dithiafulvalene ring (built on S5 and S6). Such a large folding angle is frequently observed in 1,3-dithiole rings with a *Csp*<sup>3</sup> atom in the 2-position (Krebs *et al.*, 1993, and references therein). Of particular note are the short non-bonding intramolecular S···S distances observed for S1···S5 and S6···S8, at 3.160 (2) and 3.241 (2) Å, respectively. Albeit larger than in (1), where similar short S···S distances are observed at 3.035 and 3.031 Å, this distance is still much shorter than the sum of the van der Waals radii (3.6 Å) and indicates the occurrence of a strong intramolecular S···S interaction, as discussed recently by Favard *et al.* (1998).

In the solid state, the molecules associate in pairs about inversion centres, with the shortest intermolecular S···S contact within a pair observed at 3.576 (3) Å, a slightly shorter distance than the sum of the van der Waals radii.

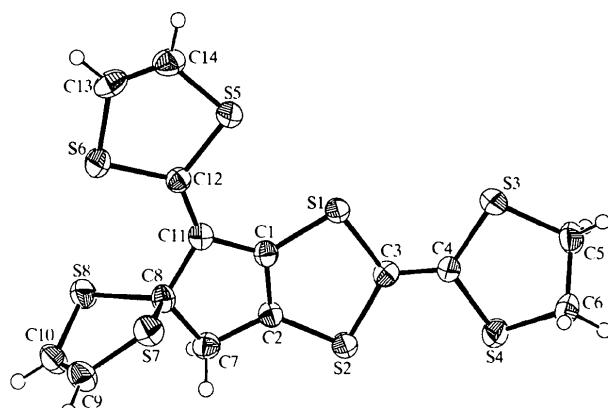


Fig. 1. The molecular structure of (2), showing 50% probability displacement ellipsoids. H atoms are drawn as spheres of arbitrary radii.

## Experimental

The title compound was obtained by elution of a solution of (1) in toluene on a silica-gel column following a Soxhlet extraction (dichloromethane) of the crude compound. The preparation of (1) has been described elsewhere (Sallé *et al.*, 1996).

### Crystal data

C <sub>14</sub> H <sub>10</sub> S <sub>8</sub>	Mo K $\alpha$ radiation
$M_r = 434.70$	$\lambda = 0.71073 \text{ \AA}$
Monoclinic	Cell parameters from 25 reflections
$P2_1/n$	$\theta = 4.8\text{--}13.1^\circ$
$a = 9.1055 (8) \text{ \AA}$	$\mu = 1.074 \text{ mm}^{-1}$
$b = 13.124 (2) \text{ \AA}$	$T = 293 (2) \text{ K}$
$c = 13.796 (3) \text{ \AA}$	Parallelepiped
$\beta = 92.429 (11)^\circ$	$0.12 \times 0.12 \times 0.12 \text{ mm}$
$V = 1647.1 (4) \text{ \AA}^3$	Red
$Z = 4$	
$D_v = 1.753 \text{ Mg m}^{-3}$	
$D_m$ not measured	

*Data collection*

Enraf–Nonius CAD-4  
diffractometer  
 $\omega/2\theta$  scans  
Absorption correction: none  
4100 measured reflections  
3163 independent reflections  
1754 reflections with  
 $I > 2\sigma(I)$

$R_{\text{int}} = 0.042$   
 $\theta_{\text{max}} = 25.97^\circ$   
 $h = -1 \rightarrow 11$   
 $k = -1 \rightarrow 16$   
 $l = -16 \rightarrow 16$   
3 standard reflections  
frequency: 60 min  
intensity decay: none

*Refinement*

Refinement on  $F^2$   
 $R(F) = 0.040$   
 $wR(F^2) = 0.086$   
 $S = 1.116$   
3163 reflections  
199 parameters  
H atoms constrained  
 $w = 1/[\sigma^2(F_o^2) + (0.0448P)^2$   
+ 0.5754P]  
where  $P = (F_o^2 + 2F_c^2)/3$

Table 1. Selected bond lengths ( $\text{\AA}$ )

S1—C1	1.755 (4)	S6—C13	1.737 (5)
S1—C3	1.776 (5)	S6—C12	1.756 (5)
S2—C2	1.726 (5)	S7—C9	1.740 (5)
S2—C3	1.767 (4)	S7—C8	1.854 (4)
S3—C4	1.757 (4)	S8—C10	1.744 (5)
S3—C5	1.818 (5)	S8—C8	1.839 (4)
S4—C4	1.760 (4)	C1—C2	1.347 (6)
S4—C6	1.810 (5)	C1—C11	1.439 (6)
S5—C14	1.730 (5)	C3—C4	1.326 (6)
S5—C12	1.761 (4)		

Data collection: CAD-4-PC (Enraf–Nonius, 1994). Cell refinement: CAD-4-PC. Data reduction: XCAD4 (Harms, 1993). Program(s) used to solve structure: SHELXS86 (Sheldrick, 1990). Program(s) used to refine structure: SHELXL93 (Sheldrick, 1993). Molecular graphics: ORTEPII (Johnson, 1976). Software used to prepare material for publication: SHELXL93.

Supplementary data for this paper are available from the IUCr electronic archives (Reference: FG1493). Services for accessing these data are described at the back of the journal.

**References**

- Benahmed-Gasmi, A. S., Frère, P., Belyasmine, A., Malik, K. M. A., Hursthouse, M. B., Moore, A. J., Bryce, M. R., Jubault, M. & Gorgues, A. (1993). *Tetrahedron Lett.* **34**, 2131–2134.  
Cooper, W. F., Kenney, N. C., Edmonds, J. C., Nagel, A., Wudl, F. & Coppens, P. (1971). *J. Chem. Soc. Chem. Commun.* pp. 889–890.  
Enraf–Nonius (1994). CAD-4-PC. Version 1.2. Enraf–Nonius, Delft, The Netherlands.  
Favard, J. F., Frère, P., Riou, A., Benahmed-Gasmi, A. S., Gorgues, A., Jubault, M. & Roncali, J. (1998). *J. Mater. Chem.* **8**, 363–366.  
Frère, P., Gorgues, A., Jubault, M., Riou, A., Gouriou, Y. & Roncali, J. (1994). *Tetrahedron Lett.* **35**, 1991–1994.  
Harms, K. (1993). XCAD4. Program for the Reduction of Enraf–Nonius CAD-4 Diffractometer Data. University of Marburg, Germany.  
Johnson, C. K. (1976). ORTEPII. Report ORNL-5138. Oak Ridge National Laboratory, Tennessee, USA.  
Krebs, F. C., Larsen, J., Boubekeur, K. & Fourmigué, M. (1993). *Acta Chem. Scand.* **47**, 910–915.

Sallé, M., Gorgues, A., Jubault, M., Boubekeur, K., Batail, P. & Carlier, R. (1996). *Bull. Soc. Chim. Fr.* **133**, 417–426.  
Sallé, M., Jubault, M., Gorgues, M., Boubekeur, K., Fourmigué, M., Batail, P. & Canadell, E. (1993). *Chem. Mater.* **5**, 1196–1198.  
Sheldrick, G. M. (1990). *Acta Cryst. A* **46**, 467–473.  
Sheldrick, G. M. (1993). SHELXL93. Program for the Refinement of Crystal Structures. University of Göttingen, Germany.

*Acta Cryst.* (1998). **C54**, 2007–2009

**Dibromo[(Z)-2-bromo-2-(hydroxymethyl)-vinyl](n-butyl)tellurium(IV)**

J. ZUKERMAN-SCHPECTOR,<sup>a\*</sup> HÉLIO A. STEFANI,<sup>b</sup> DIOGO DE O. SILVA,<sup>b</sup> ANTONIO L. BRAGA,<sup>c</sup> LUCIANO DORNELLES,<sup>c</sup> CLAUDIO DA C. SILVEIRA<sup>c</sup> AND I. CARACELLI<sup>d</sup>

<sup>a</sup>Laboratório de Cristalografia, Estereodinâmica e Modelagem Molecular, Departamento Química, Universidade Federal de São Carlos, Caixa Postal 676, 13565-905 São Carlos, SP, Brazil, and Instituto de Química-USP-SP, Brazil;

<sup>b</sup>Faculdade de Ciências Farmacêuticas, USP, São Paulo, SP, Brazil, <sup>c</sup>Departamento de Química, Universidade Federal de Santa Maria, Santa Maria, RS, Brazil, and <sup>d</sup>Departamento de Física, Universidade Federal de São Carlos, SP, Brazil.

E-mail: julio@power.ufscar.br

(Received 17 April 1998; accepted 14 July 1998)

**Abstract**

In the title compound,  $[\text{TeBr}_2(\text{C}_4\text{H}_9)(\text{C}_3\text{H}_4\text{BrO})]$  or  $\text{C}_7\text{H}_{13}\text{Br}_3\text{OTe}$ , the primary geometry about the  $\text{Te}^{IV}$  atom is a pseudo-trigonal-bipyramidal arrangement with axial bromines and one equatorial position vacant. If an intermolecular secondary  $\text{Te}\cdots\text{O}$  bond of  $3.041(5)\text{\AA}$ , *trans* to the  $\text{Te}=\text{C}(\text{vinylic})$  bond, is taken into consideration, the structure may be regarded as pseudo-octahedral. Distances and angles are:  $\text{Te}=\text{Br}$   $2.7295(10)$  and  $2.6115(10)$ ,  $\text{Te}=\text{C}$   $2.092(6)$  and  $2.134(7)\text{\AA}$ ,  $\text{Br}=\text{Te}=\text{Br}$   $176.59(3)$ ,  $\text{Br}=\text{Te}=\text{C}$   $88.87(19)$ ,  $89.0(3)$ ,  $89.65(19)$  and  $88.2(3)$ , and  $\text{C}=\text{Te}=\text{C}$   $99.7(3)^\circ$ . The lattice is formed by hydrogen-bonded centrosymmetric dimers [ $\text{O}\cdots\text{Br} = 3.399(6)\text{\AA}$ ], which, in turn, are linked by the intermolecular secondary  $\text{Te}\cdots\text{O}$  bond.

**Comment**

Vinylic tellurides are intermediates in the synthesis of vinylolithium compounds, which are, in turn, important intermediates in organic synthesis, either as precursors of the widely used vinylcuprate compounds or as nucleophiles leading to chain-elongation products by